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	Type	L #	Hits	Search Text	DBs	Time Stamp	Comments
1	IS&R	L1	4153	(382/141-149,199) .CCLS .	US- PGPUB; USPAT	2007/06/23 12:35	
2	IS&R	L2	342	(348/86,92) .CCLS .	US- PGPUB; USPAT	2007/06/23 12:36	
3	IS&R	L3	1225	(702/33,35,127) .CCLS .	US- PGPUB; USPAT	2007/06/23 12:37	
4	BRS	L4	58106	(substrate\$1 or surface\$1) same (inspect\$4 or measur\$6 or examin\$6) same (defect\$4 or error\$1 or flaw\$1 or void\$1 or crack\$1)	US- PGPUB; USPAT	2007/06/23 12:39	
5	BRS	L5	4920	4 same (stage\$1 or chamber\$1)	US- PGPUB; USPAT	2007/06/23 12:41	
6	BRS	L6	324	4 same ((second or multiple\$1 or sevral or plural\$4) near4 (stage\$1 or chamber\$1))	US- PGPUB; USPAT	2007/06/23 12:41	
7	BRS	L7	45	6 and (edge\$1 near5 bead\$1 near5 (remov\$4 or eliminat\$4 or discard\$3 or reject\$4 or correct\$4))	US- PGPUB; USPAT	2007/06/23 13:15	
8	BRS	L9	0	2 and 7	US- PGPUB; USPAT	2007/06/23 12:43	

	Type	L #	Hits	Search Text	DBs	Time Stamp	Comments
9	BRS	L8	2	1 and 7	US- PGPUB; USPAT	2007/06/23 12:47	
10	BRS	L11	1	"6829559".pn.	US- PGPUB; USPAT	2007/06/23 12:48	
11	BRS	L10	2	3 and 7	US- PGPUB; USPAT	2007/06/23 12:56	
12	BRS	L12	1	7 and (edge near3 exposure)	US- PGPUB; USPAT	2007/06/23 13:01	
13	BRS	L13	6	(edge\$1 near3 beads\$1) same (edge near3 exposure) same (wafer\$1 or semiconductor\$3 or substrate\$1) same (measur\$6 or inspect\$4)	US- PGPUB; USPAT	2007/06/23 13:07	
14	BRS	L14	327360	(substrate\$1 near5 (measur\$6 or inspect\$4)) same (stage\$1 or chamber\$1)	US- PGPUB; USPAT	2007/06/23 13:05	
15	BRS	L15	23290	14 same (defect\$4 or crack\$1 or flaw\$1 or error\$1 or void\$1)	US- PGPUB; USPAT	2007/06/23 13:06	
16	BRS	L16	1896	15 same ((first or second or third or plural\$4 or multiple or several) near3 stage\$1)	US- PGPUB; USPAT	2007/06/23 13:06	
17	BRS	L17	4	16 same (edge\$1 near3 bead\$1)	US- PGPUB; USPAT	2007/06/23 13:13	

	Type	L #	Hits	Search Text	DBs	Time Stamp	Comments
18	BRS	L18	1	17 and (edge\$1 near3 exposure)	US- PGPUB; USPAT	2007/06/23 13:08	
19	BRS	L19	56	16 and robot	USPAT	2007/06/23 13:13	
20	BRS	L20	1	19 and (edge\$1 near3 bead\$1)	US- PGPUB; USPAT	2007/06/23 13:13	
21	BRS	L21	42	7 and robot	US- PGPUB; USPAT	2007/06/23 13:15	
22	BRS	L23	0	2 and 21	US- PGPUB; USPAT	2007/06/23 13:15	
23	BRS	L22	2	1 and 21	US- PGPUB; USPAT	2007/06/23 13:15	
24	BRS	L24	2	3 and 21	US- PGPUB; USPAT	2007/06/23 13:15	

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	Type	L #	Hits	Search Text	DBs	Time Stamp	Comments
1	BRS	L.8	1	((substrate near3 inspect\$4) and (second near3 stage\$1) and defect\$1 and edge\$1 and robot).clm.	US- PGPUB	2007/06/23 13:43	
2	BRS	L.9	1	((substrate near3 inspect\$4) and (second near3 stage\$1) and defect\$1 and edge\$1).clm.	US- PGPUB	2007/06/23 13:43	

Day : Saturday
 Date: 6/23/2007

Time: 13:44:22

PALM INTRANET**Inventor Name Search Result**

Your Search was:

Last Name = JUN

First Name = CHUNG-SAM

Application#	Patent#	Status	Date Filed	Title	Inventor Name
09162267	6366688	150	09/29/1998	APPARATUS AND METHOD FOR CONTACT FAILURE INSPECTION IN SEMICONDUCTOR DEVICES	JUN, CHUNG-SAM
09584671	6528333	150	06/01/2000	METHOD OF AND DEVICE FOR DETECTING MICRO-SCRATCHES	JUN, CHUNG-SAM
09671207	6515293	150	09/28/2000	METHOD AND APPARATUS FOR DETECTING THICKNESS OF THIN LAYER FORMED ON A WAFER	JUN, CHUNG-SAM
09685094	6544802	150	10/11/2000	WAFER INSPECTION SYSTEM AND METHOD FOR SELECTIVELY INSPECTING CONDUCTIVE PATTERN DEFECTS	JUN, CHUNG-SAM
09864398	6449037	150	05/25/2001	METHOD OF AND DEVICE FOR DETECTING MICRO-SCRATCHES	JUN, CHUNG-SAM
09949111	7027638	150	09/07/2001	WAFER COLOR VARIATION CORRECTING METHOD, SELECTIVE WAFER DEFECT DETECTING METHOD, AND COMPUTER READABLE RECORDING MEDIA FOR THE SAME	JUN, CHUNG-SAM
09977238	6870948	150	10/16/2001	METHOD AND APPARATUS FOR NUMERICALLY ANALYZING GRAIN GROWTH ON SEMICONDUCTOR WAFER USING SEM IMAGE	JUN, CHUNG-SAM
09988683	6650408	150	11/20/2001	METHOD FOR INSPECTING A POLISHING PAD IN A SEMICONDUCTOR	JUN, CHUNG-SAM

				MANUFACTURING PROCESS, AN APPARATUS FOR PERFORMING THE METHOD, AND A POLISHING DEVICE ADOPTING THE APPARATUS	
<u>10012562</u>	6850332	150	12/12/2001	METHOD FOR MEASURING STEP DIFFERENCE IN A SEMICONDUCTOR DEVICE AND APPARATUS FOR PERFORMING THE SAME	JUN, CHUNG-SAM
<u>10338832</u>	6803241	150	01/09/2003	METHOD OF MONITORING CONTACT HOLE OF INTEGRATED CIRCUIT USING CORONA CHARGES	JUN, CHUNG-SAM
<u>10634756</u>	6800863	150	08/06/2003	METHOD FOR MONITORING AN ION IMPLANTER AND ION IMPLANTER HAVING A SHADOW JIG FOR PERFORMING THE SAME	JUN, CHUNG-SAM
<u>10661632</u>	Not Issued	60	09/15/2003	Method and apparatus for analyzing a sample employing fast fourier transformation	JUN, CHUNG-SAM
<u>10661633</u>	Not Issued	71	09/15/2003	Apparatus and method for inspecting a substrate	JUN, CHUNG-SAM
<u>10694882</u>	6815236	150	10/29/2003	METHOD OF MEASURING A CONCENTRATION OF A MATERIAL AND METHOD OF MEASURING A CONCENTRATION OF A DOPANT OF A SEMICONDUCTOR DEVICE	JUN, CHUNG-SAM
<u>10704753</u>	6927077	150	11/12/2003	METHOD AND APPARATUS FOR MEASURING CONTAMINATION OF A SEMICONDUCTOR SUBSTRATE	JUN, CHUNG-SAM
<u>10718817</u>	7081952	150	11/24/2003	METHOD AND APPARATUS FOR OBTAINING AN IMAGE USING A SELECTIVE COMBINATION OF WAVELENGTHS OF LIGHT	JUN, CHUNG-SAM
<u>10777922</u>	7113274	150	02/11/2004	METHOD AND APPARATUS FOR INSPECTING A SUBSTRATE	JUN, CHUNG-SAM
<u>10786137</u>	Not Issued	71	02/26/2004	Method and apparatus for classifying defects of an object	JUN, CHUNG-SAM

<u>10787765</u>	Not Issued	93	02/27/2004	METHOD AND APPARATUS FOR INSPECTING AN EDGE EXPOSURE AREA OF A WAFER	JUN, CHUNG-SAM
<u>10787772</u>	7186577	150	02/27/2004	METHOD FOR MONITORING A DENSITY PROFILE OF IMPURITIES	JUN, CHUNG-SAM
<u>10789445</u>	7046760	150	03/01/2004	METHOD OF MEASURING AND CONTROLLING CONCENTRATION OF DOPANTS OF A THIN FILM	JUN, CHUNG-SAM
<u>10877684</u>	Not Issued	161	06/25/2004	Method and apparatus for inspecting a wafer surface	JUN, CHUNG-SAM
<u>10903852</u>	Not Issued	93	07/30/2004	METHOD AND APPARATUS FOR INSPECTING DEFECTS	JUN, CHUNG-SAM
<u>10909238</u>	Not Issued	30	07/30/2004	Method and apparatus for detecting a photolithography processing error, and method and apparatus for monitoring a photolithography process	JUN, CHUNG-SAM
<u>10912559</u>	Not Issued	61	08/06/2004	Apparatus and method for measuring a thickness of a substrate	JUN, CHUNG-SAM
<u>11012005</u>	Not Issued	93	12/13/2004	SYSTEMS AND METHODS FOR MEASURING DISTANCE OF SEMICONDUCTOR PATTERNS	JUN, CHUNG-SAM
<u>11016247</u>	7220173	150	12/20/2004	WAFER HOLDER AND WAFER CONVEYOR SYSTEM EQUIPPED WITH THE SAME	JUN, CHUNG-SAM
<u>11028895</u>	Not Issued	41	01/04/2005	Electron-beam inspection apparatus and methods of inspecting through-holes using clustered nanotube arrays	JUN, CHUNG-SAM
<u>11054752</u>	Not Issued	30	02/09/2005	Apparatus and method for measuring substrates	JUN, CHUNG-SAM
<u>11175363</u>	7186280	150	07/07/2005	METHOD OF INSPECTING A LEAKAGE CURRENT CHARACTERISTIC OF A DIELECTRIC LAYER AND APPARATUS FOR PERFORMING THE METHOD	JUN, CHUNG-SAM
<u>11180504</u>	Not Issued	30	07/12/2005	Method of forming a three-dimensional image of a pattern to be inspected and apparatus for performing the same	JUN, CHUNG-SAM

<u>11191069</u>	7197426	150	07/28/2005	METHOD AND APPARATUS FOR MEASURING THICKNESS OF METAL LAYER	JUN, CHUNG-SAM
<u>11198314</u>	Not Issued	30	08/08/2005	Image processing method	JUN, CHUNG-SAM
<u>11207772</u>	Not Issued	30	08/22/2005	Method and apparatus for inspecting substrate pattern	JUN, CHUNG-SAM
<u>11253028</u>	Not Issued	30	10/17/2005	Method of inspecting defects and apparatus for performing the same	JUN, CHUNG-SAM
<u>11421019</u>	Not Issued	25	05/30/2006	METHOD OF CLASSIFYING DEFECTS	JUN, CHUNG-SAM
<u>11423677</u>	Not Issued	25	06/12/2006	OPTICAL INSPECTION TOOL HAVING LENS UNIT WITH MULTIPLE BEAM PATHS FOR DETECTING SURFACE DEFECTS OF A SUBSTRATE AND METHODS OF USING SAME	JUN, CHUNG-SAM
<u>11428804</u>	Not Issued	30	07/05/2006	METHOD OF INSPECTING A SUBSTRATE USING ULTRASONIC WAVES AND APPARATUS FOR PERFORMING THE SAME	JUN, CHUNG-SAM
<u>11461312</u>	Not Issued	30	07/31/2006	METHOD OF MEASURING A SURFACE VOLTAGE OF AN INSULATING LAYER	JUN, CHUNG-SAM
<u>11461726</u>	Not Issued	30	08/01/2006	METHOD AND APPARATUS FOR INSPECTING TARGET DEFECTS ON A WAFER	JUN, CHUNG-SAM
<u>11462954</u>	Not Issued	30	08/07/2006	METHOD OF INSPECTING A DEFECT ON A SUBSTRATE	JUN, CHUNG-SAM
<u>11463281</u>	Not Issued	30	08/08/2006	METHOD AND APPARATUS FOR INSPECTING A SUBSTRATE	JUN, CHUNG-SAM
<u>11476651</u>	Not Issued	30	06/29/2006	Method of inspecting for defects and apparatus for performing the method	JUN, CHUNG-SAM
<u>11498017</u>	Not Issued	30	08/03/2006	Adsorption apparatus, semiconductor device manufacturing facility comprising the same, and method of recycling perfluorocompounds	JUN, CHUNG-SAM
<u>11564726</u>	Not Issued	30	11/29/2006	METHOD OF SCANNING A SUBSTRATE, AND METHOD AND APPARATUS FOR	JUN, CHUNG-SAM

				ANALYZING CRYSTAL CHARACTERISTICS	
<u>11566637</u>	Not Issued	25	12/04/2006	TEST PATTERN AND METHOD FOR MEASURING SILICON ETCHING DEPTH	JUN, CHUNG-SAM
<u>11675016</u>	Not Issued	30	02/14/2007	METHOD AND APPARATUS FOR CONTROLLING LIGHT INTENSITY AND FOR EXPOSING A SEMICONDUCTOR SUBSTRATE	JUN, CHUNG-SAM
<u>11702599</u>	Not Issued	25	02/06/2007	Method of measuring critical dimension	JUN, CHUNG-SAM
<u>11703095</u>	Not Issued	25	02/07/2007	Apparatus and method for examining spectral characteristics of an object	JUN, CHUNG-SAM
<u>11710543</u>	Not Issued	25	02/26/2007	Method of inspecgin a leakage current characteristic of a dielectric layer	JUN, CHUNG-SAM

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PALM INTRANET**Inventor Name Search Result**

Your Search was:

Last Name = JUN

First Name = CHUNG-SAM

Application#	Patent#	Status	Date Filed	Title	Inventor Name
11710579	Not Issued	17	02/26/2007	Apparatus for monitoring a density profile of impurities	JUN, CHUNG-SAM
11783534	Not Issued	30	04/10/2007	Wafer holder and wafer conveyor equipped with the same	JUN, CHUNG-SAM
60090137	Not Issued	159	06/22/1998	CONTACT FAILURE INSPECTION METHOD OF SEMICONDUCTOR DEVICES, INSPECTION SYSTEM, AND METHOD OF MANUFACTURING SEMICONDUCTOR DEVICES THEREBY	JUN, CHUNG-SAM

Inventor Search Completed: No Records to Display.

Search Another: Inventor**Last Name**

jun

First Name

chung-sam

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Day : Saturday
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PALM INTRANET**Inventor Name Search Result**

Your Search was:

Last Name = CHOI

First Name = SUN-YONG

Application#	Patent#	Status	Date Filed	Title	Inventor Name
08501168	5755469	150	07/11/1995	WAFER TRANSFER BLADE	CHOI, SUN-YONG
08524436	5676824	250	09/06/1995	WATER PURIFIER WITH MEANS FOR INDICATING WHEN FILTER REPLACEMENT IS DUE AND FOR AUTOMATICALLY INITIATING A MEMBRANE WASHING STEP	CHOI, SUN-YONG
08558984	Not Issued	161	11/16/1995	PUMP CONTROL DEVICE FOR WATER PURIFIER	CHOI, SUN-YONG
08951325	Not Issued	161	10/16/1997	WATER PURIFIER	CHOI, SUN-YONG
10447104	6869215	150	05/29/2003	METHOD AND APPARATUS FOR DETECTING CONTAMINANTS IN ION-IMPLANTED WAFER	CHOI, SUN-YONG
10634756	6800863	150	08/06/2003	METHOD FOR MONITORING AN ION IMPLANTER AND ION IMPLANTER HAVING A SHADOW JIG FOR PERFORMING THE SAME	CHOI, SUN-YONG
10661632	Not Issued	60	09/15/2003	Method and apparatus for analyzing a sample employing fast fourier transformation	CHOI, SUN-YONG
10661633	Not Issued	71	09/15/2003	Apparatus and method for inspecting a substrate	CHOI, SUN-YONG
10694882	6815236	150	10/29/2003	METHOD OF MEASURING A CONCENTRATION OF A MATERIAL AND METHOD OF MEASURING A CONCENTRATION OF A DOPANT OF A SEMICONDUCTOR DEVICE	CHOI, SUN-YONG

<u>10704753</u>	<u>6927077</u>	150	11/12/2003	METHOD AND APPARATUS FOR MEASURING CONTAMINATION OF A SEMICONDUCTOR SUBSTRATE	CHOI, SUN-YONG
<u>10777922</u>	<u>7113274</u>	150	02/11/2004	METHOD AND APPARATUS FOR INSPECTING A SUBSTRATE	CHOI, SUN-YONG
<u>10786137</u>	Not Issued	71	02/26/2004	Method and apparatus for classifying defects of an object	CHOI, SUN-YONG
<u>10787765</u>	Not Issued	93	02/27/2004	METHOD AND APPARATUS FOR INSPECTING AN EDGE EXPOSURE AREA OF A WAFER	CHOI, SUN-YONG
<u>10787772</u>	<u>7186577</u>	150	02/27/2004	METHOD FOR MONITORING A DENSITY PROFILE OF IMPURITIES	CHOI, SUN-YONG
<u>10789445</u>	<u>7046760</u>	150	03/01/2004	METHOD OF MEASURING AND CONTROLLING CONCENTRATION OF DOPANTS OF A THIN FILM	CHOI, SUN-YONG
<u>10877684</u>	Not Issued	161	06/25/2004	Method and apparatus for inspecting a wafer surface	CHOI, SUN-YONG
<u>10903852</u>	Not Issued	93	07/30/2004	METHOD AND APPARATUS FOR INSPECTING DEFECTS	CHOI, SUN-YONG
<u>10909238</u>	Not Issued	30	07/30/2004	Method and apparatus for detecting a photolithography processing error, and method and apparatus for monitoring a photolithography process	CHOI, SUN-YONG
<u>10912559</u>	Not Issued	61	08/06/2004	Apparatus and method for measuring a thickness of a substrate	CHOI, SUN-YONG
<u>11012005</u>	Not Issued	93	12/13/2004	SYSTEMS AND METHODS FOR MEASURING DISTANCE OF SEMICONDUCTOR PATTERNS	CHOI, SUN-YONG
<u>11710579</u>	Not Issued	17	02/26/2007	Apparatus for monitoring a density profile of impurities	CHOI, SUN-YONG

Inventor Search Completed: No Records to Display.

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choi

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sun-yong

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Day : Saturday
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PALM INTRANET**Inventor Name Search Result**

Your Search was:

Last Name = KIM

First Name = KWANG-SOO

Application#	Patent#	Status	Date Filed	Title	Inventor Name
07781365	Not Issued	161	10/23/1991	POWER SUPPLY CIRCUIT FOR AN UNIVERSAL MOTOR	KIM, KWANG-SOO
08670756	5693555	150	06/21/1996	METHOD FOR FABRICATING BICMOS DEVICE	KIM, KWANG-SOO
08870388	5989043	150	06/06/1997	POWER SWITCH ON/OFF MECHANISM OF PLUG-IN UNIT DRIVEN BY AN INSERTION/ EJECTION DEVICE IN A PRINTED CIRCUIT BOARD	KIM, KWANG-SOO
08882485	5963798	150	06/25/1997	FABRICATION METHOD OF CMOS DEVICE HAVING BURIED IMPLANTED LAYERS FOR LATERAL ISOLATION (BILLI)	KIM, KWANG-SOO
08883202	5989949	150	06/26/1997	METHOD OF MANUFACTURING A COMPLEMENTARY METAL-OXIDE SEMICONDUCTOR DEVICE	KIM, KWANG-SOO
09414329	6291357	250	10/06/1999	METHOD AND APPARATUS FOR ETCHING A SUBSTRATE WITH REDUCED MICROLOADING	KIM, KWANG-SOO
09688748	6525189	150	10/16/2000	MULTIMERIZED DBH ENHANCER DOMAINS	KIM, KWANG-SOO
09938208	6489248	250	08/23/2001	METHOD AND APPARATUS FOR ETCH PASSIVATING AND ETCHING A SUBSTRATE	KIM, KWANG-SOO
10092908	Not Issued	161	03/07/2002	Methods and reagents for identifying compounds and mutations that modulate dopamine beta-hydroxylase activity	KIM, KWANG-SOO

<u>10277345</u>	Not Issued	41	10/21/2002	Multimerized enhancer domains for cell-specific expression	KIM, KWANG-SOO
<u>10282946</u>	Not Issued	160	10/29/2002	Multimerized DBH enhancer domains	KIM, KWANG-SOO
<u>10350257</u>	<u>7037715</u>	150	01/23/2003	MULTIMERIZED DBH ENHANCER DOMAINS	KIM, KWANG-SOO
<u>10661633</u>	Not Issued	71	09/15/2003	Apparatus and method for inspecting a substrate	KIM, KWANG-SOO
<u>10694882</u>	<u>6815236</u>	150	10/29/2003	METHOD OF MEASURING A CONCENTRATION OF A MATERIAL AND METHOD OF MEASURING A CONCENTRATION OF A DOPANT OF A SEMICONDUCTOR DEVICE	KIM, KWANG-SOO
<u>10734342</u>	<u>7060185</u>	150	12/11/2003	SEWAGE TREATMENT APPARATUS USING SELF-GRANULATED ACTIVATED SLUDGE AND SEWAGE TREATMENT METHOD THEREOF	KIM, KWANG-SOO
<u>10911661</u>	Not Issued	30	08/05/2004	Jelly-roll type electrode assembly and secondary battery including the same	KIM, KWANG-SOO
<u>11106569</u>	Not Issued	83	04/15/2005	Confocal scanning microscope using two nipkow disks	KIM, KWANG-SOO
<u>11127036</u>	Not Issued	30	05/10/2005	Dual bias frequency plasma reactor with feedback control of E.S.C. voltage using wafer voltage measurement at the bias supply output	KIM, KWANG-SOO
<u>11132352</u>	Not Issued	71	05/19/2005	Wafer inspection system and method thereof	KIM, KWANG-SOO
<u>11236236</u>	Not Issued	30	09/27/2005	Vehicle-monitoring device and method using optical flow	KIM, KWANG-SOO
<u>11249092</u>	Not Issued	30	10/12/2005	Apparatus and method for recognizing an image	KIM, KWANG-SOO
<u>11335216</u>	Not Issued	30	01/19/2006	Apparatus and method for normalizing face image used for detecting drowsy driving	KIM, KWANG-SOO
<u>11428804</u>	Not Issued	30	07/05/2006	METHOD OF INSPECTING A SUBSTRATE USING ULTRASONIC WAVES AND APPARATUS FOR PERFORMING THE SAME	KIM, KWANG-SOO

<u>11583796</u>	Not Issued	30	10/20/2006	Fabrication method and structure for providing a recessed channel in a nonvolatile memory device	KIM, KWANG-SOO
<u>11606232</u>	Not Issued	30	11/29/2006	Traffic information providing apparatus and operating method using automatically scrolling display screen	KIM, KWANG-SOO
<u>11672362</u>	Not Issued	25	02/07/2007	METHOD OF FEEDBACK CONTROL OF ESC VOLTAGE USING WAFER VOLTAGE MEASUREMENT AT THE BIAS SUPPLY OUTPUT	KIM, KWANG-SOO
<u>11674817</u>	Not Issued	19	01/01/0001	DIAGNOSIS AND TREATMENT OF ATTENTIONAL DISORDERS	KIM, KWANG-SOO
<u>11679047</u>	Not Issued	25	02/26/2007	METHODS FOR ETCHING HIGH ASPECT RATIO FEATURES	KIM, KWANG-SOO
<u>11725179</u>	Not Issued	17	03/16/2007	Method and apparatus for notifying departure time using schedule information	KIM, KWANG-SOO
<u>60159695</u>	Not Issued	159	10/15/1999	MULTIMERIZED DBH ENHANCER DOMAINS	KIM, KWANG-SOO
<u>60274095</u>	Not Issued	159	03/07/2001	Pathogenic mutations of the human dopamine B-hydroxylase gene	KIM, KWANG-SOO
<u>60343780</u>	Not Issued	159	10/19/2001	Multimerized enhancer domains for cell-specific expression	KIM, KWANG-SOO
<u>60773459</u>	Not Issued	159	02/15/2006	Diagnosis and treatment of attentional disorders	KIM, KWANG-SOO
<u>60833405</u>	Not Issued	20	07/26/2006	Buried circumferential electrode microcavity plasma device arrays, and self-patterned formation method	KIM, KWANG-SOO
<u>10334352</u>	7093189	150	12/31/2002	METHOD AND DEVICE FOR PERFORMING SOFT DECISION DECODING ON REED-MULLER CODES USING DECISION BY MAJORITY	KIM, KWANG-SOON
<u>10532734</u>	Not Issued	30	10/03/2005	Frequency hopping ofdma method using symbols of comb pattern	KIM, KWANG-SOON
<u>10536593</u>	Not Issued	30	09/28/2005	Method and apparatus for embodying and synchronizing downlink signal in mobile communication system and method for searching cell using the same	KIM, KWANG-SOON

<u>10539166</u>	Not Issued	25	03/03/2006	Apparatus and method for signal constitution for downlink of ofdma-based cellular system	KIM, KWANG-SOON
<u>10577034</u>	Not Issued	20	01/23/2007	Downlink signal configuring method and device in mobile communication system, and synchronization and cell searching method and device using the same	KIM, KWANG-SOON
<u>10579892</u>	Not Issued	20	01/23/2007	Method for partitioning resource space, assigning physical channel, and allocating power in ofdma-based cellular system	KIM, KWANG-SOON
<u>10582636</u>	Not Issued	20	06/12/2006	System and method for transmitting random access data using orthogonal frequency division multiple access	KIM, KWANG-SOON
<u>10606822</u>	Not Issued	61	06/26/2003	Digital filter for software-defined radio system, digital intermediate frequency signal processing apparatus having the digital filter, and method thereof	KIM, KWANG-SOON
<u>10696897</u>	<u>7178081</u>	150	10/29/2003	SIMPLIFIED MESSAGE-PASSING DECODER FOR LOW-DENSITY PARITY-CHECK CODES	KIM, KWANG-SOON
<u>10723528</u>	<u>7123887</u>	150	11/25/2003	ADAPTIVE TRANSMISSION AND RECEIVING METHOD AND DEVICE IN WIRELESS COMMUNICATION SYSTEM WITH MULTIPLE ANTENNAS	KIM, KWANG-SOON
<u>10848921</u>	Not Issued	30	05/19/2004	Adaptive transmitting and receiving device and method in wireless communication system using frequency division duplexing	KIM, KWANG-SOON
<u>10941197</u>	Not Issued	41	09/14/2004	Apparatus for OFDMA transmission and reception for coherent detection in uplink of wireless communication system and method thereof	KIM, KWANG-SOON
<u>10964122</u>	Not Issued	89	10/12/2004	Apparatus for encoding and decoding of low-density parity-check codes, and method thereof	KIM, KWANG-SOON
<u>11000290</u>	Not Issued	30	11/29/2004	Apparatus and method for erasure detection and soft-decision decoding in cellular system	KIM, KWANG-SOON

				receiver	
<u>11401484</u>	Not Issued	30	04/11/2006	Apparatus and method for estimating frequency offset in Orthogonal Frequency Division Multiplexing system	KIM, KWANG-SOON
<u>11438667</u>	Not Issued	30	05/23/2006	Apparatus and method for generating channel information and apparatus and method for adaptive transmission employing the same	KIM, KWANG-SOON

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Application#	Patent#	Status	Date Filed	Title	Inventor Name
10661633	Not Issued	71	09/15/2003	Apparatus and method for inspecting a substrate	KIM, JOO-WOO
10883711	7235411	150	07/06/2004	METHOD FOR ALIGNING A WAFER AND APPARATUS FOR PERFORMING THE SAME	KIM, JOO-WOO
10999066	7155366	150	11/30/2004	APPARATUS AND METHOD FOR INSPECTING PATTERNS ON WAFERS	KIM, JOO-WOO

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